Application/Control No. Applicant(s)/Patent Under Reexamination 10/822,898 CLAY ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2179 Ba Huynh **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY 05-1999 Wakabayashi et al. US-5,903,634 379/127.01 Α US-2003/0200159 10-2003 Kay et al. 705/28 В * US-2004/0100479 05-2004 Nakano et al. 345/700 С US-2003/0117365 06-2003 D Shteyn, Yevgeniy Eugene 345/156 * Ε US-2002/0041292 04-2002 Son et al. 345/810 US-F US-G US-Н US-1 US-

FOREIGN PATENT DOCUMENTS

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